

Search Notes

Application/Control No.

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Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

SHEN ET AL.

Art Unit

1794

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search	10/9/2007	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR